Gaussian Process Regression for WDM System Performance Prediction

Gaussian process regression is numerically and experimentally investigated to predict the bit error rate of a 24 x 28 CiBd QPSK WDM system. The proposed method produces accurate predictions from multi-dimensional and sparse measurement data.

**General information**
State: Published
Organisations: Department of Photonics Engineering, Networks Technology and Service Platforms, High-Speed Optical Communication, Centre of Excellence for Silicon Photonics for Optical Communications, MLytico
Contributors: Wass, J., Thrane, J., Piels, M., Jones, R. T., Zibar, D.
Number of pages: 3
Publication date: 2017

**Host publication information**
Title of host publication: Optical Fiber Communication Conference 2017
Publisher: Optical Society of America (OSA)
Article number: Tu3D.7
ISBN (Print): 978-1-943580-23-1
(2017 Optical Fiber Communications Conference and Exhibition (ofc)).
DOIs:
10.1364/OFC.2017.Tu3D.7

**Bibliographical note**
From the session: Linear and Nonlinear Multicarrier Systems (Tu3D)
Source: FindIt
Source-ID: 2372167883
Research output: Research - peer-review › Article in proceedings – Annual report year: 2017